SHEET <u>1</u> OF <u>1</u>

INIEC	PMATION		SLIBE	ATTORNEY'S DKT No. 015780-034		APPLICATION NO. 09/632,631						
INFORMATION SURE				APPLICANT Naulleau et al.								
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance <u>and</u> not considered. Include copy of this form with next communication to applicant.

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